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# 3.3 V, 161.1328 MHz LVPECL Clock Oscillator

The NBXSBA008, single frequency, crystal oscillator (XO) is designed to meet today's requirements for 3.3 V LVPECL clock generation applications. The device uses a high Q fundamental crystal and Phase Lock Loop (PLL) multiplier to provide 161.1328 MHz, ultra low jitter and phase noise LVPECL differential output.

This device is a member of ON Semiconductor's PureEdge  $^{\text{\tiny M}}$  clock family that provides accurate and precision clock solutions.

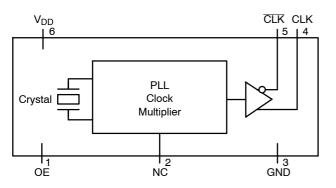
Available in 5 mm x 7 mm SMD (CLCC) package on 16 mm tape and reel in quantities of 1,000.

### Features

- LVPECL Differential Output
- Uses High Q Fundamental Mode Crystal and PLL Multiplier
- Ultra Low Jitter and Phase Noise 0.4 ps (12 kHz 20 MHz)
- Output Frequency 161.1328 MHz
- Hermetically Sealed Ceramic SMD Package
- RoHS Compliant
- Operating Range 3.3 V ±10%
- Total Frequency Stability ±50 PPM
- This is a Pb–Free Device

#### Applications

- Networking
- WAN
- IOGE



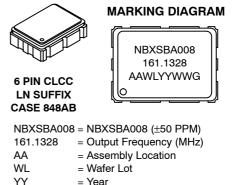
#### Figure 1. Simplified Logic Diagram

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# **ON Semiconductor®**

http://onsemi.com



= Work Week

WW

G

- = Pb-Free Package
- = FD-I Tee Fackage

#### **ORDERING INFORMATION**

Dev	ice	Package	Shipping†
NBXSBA00	8LN1TAG	CLCC-6 (Pb-Free)	1000/Tape & Reel
NBXSBA00	8LNHTAG	CLCC-6 (Pb-Free)	100/Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

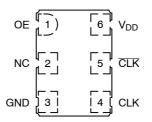


Figure 2. Pin Connections (Top View)

#### **Table 1. PIN DESCRIPTION**

Pin No.	Symbol	I/O	Description
1	OE	LVTTL/LVCMOS Control Input	Output Enable Pin. When left floating pin defaults to logic HIGH and output is active. See OE pin description Table 2.
2	NC	N/A	No Connect.
3	GND	Power Supply	Ground 0 V
4	CLK	LVPECL Output	Non–Inverted Clock Output. Typically loaded with 50 $\Omega$ receiver termination resistor to $V_{TT}$ = $V_{DD}$ – 2 V.
5	CLK	LVPECL Output	Inverted Clock Output. Typically loaded with 50 $\Omega$ receiver termination resistor to $V_{TT}$ = $V_{DD}$ – 2 V.
6	V <sub>DD</sub>	Power Supply	Positive power supply voltage. Voltage should not exceed 3.3 V $\pm 10\%.$

#### Table 2. OUTPUT ENABLE TRI-STATE FUNCTION

OE Pin	Output Pins	
Open	Active	
HIGH Level	Active	
LOW Level	High Z	

#### **Table 3. ATTRIBUTES**

Characteristic		Value	
Internal Default State Resistor		170 kΩ	
ESD Protection Human Body Model Machine Model			
Meets or Exceeds JEDEC Standard EIA/JESD78 IC Latchup Test			

1. For additional Moisture Sensitivity information, refer to Application Note AND8003/D.

#### Table 4. MAXIMUM RATINGS

Symbol	Parameter	Condition 1	Condition 2	Rating	Units
V <sub>DD</sub>	Positive Power Supply	GND = 0 V		4.6	V
l <sub>out</sub>	LVPECL Output Current	Continuous Surge		25 50	mA
T <sub>A</sub>	Operating Temperature Range			-40 to +85	°C
T <sub>stg</sub>	Storage Temperature Range			-55 to +120	°C
T <sub>sol</sub>	Wave Solder	See Figure 5		260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

Table 5. DC CHARACTERISTICS (V <sub>DD</sub> = $3.3 \text{ V} \pm 10\%$ , GND = $0 \text{ V}$ , T <sub>A</sub> = $-40^{\circ}\text{C}$ to $+85^{\circ}\text{C}$ ) (Note 2)	
--	--

Symbol	Characteristic		Conditions	Min.	Тур.	Max.	Units
I <sub>DD</sub>	Power Supply Current				75	100	mA
VIH	OE Input HIGH Voltage			2000		V <sub>DD</sub>	mV
V <sub>IL</sub>	OE Input LOW Voltage			GND – 300		800	mV
Ι <sub>ΙΗ</sub>	Input HIGH Current	OE FSEL		-100 -100		+100 +100	μΑ
Ι <sub>ΙL</sub>	Input LOW Current	OE FSEL		-100 -100		+100 +100	μΑ
V <sub>OH</sub>	Output HIGH Voltage		V <sub>DD</sub> = 3.3 V	V <sub>DD</sub> -1195 2105		V <sub>DD</sub> -945 2355	mV
V <sub>OL</sub>	Output LOW Voltage		V <sub>DD</sub> = 3.3 V	V <sub>DD</sub> -1945 1355		V <sub>DD</sub> -1600 1700	mV
V <sub>OUTPP</sub>	Output Voltage Amplitude				680		mV

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

2. Measurement taken with outputs terminated with 50  $\Omega$  to V\_{DD} – 2.0 V. See Figure 4.

Symbol	Characteristic	Conditions	Min.	Тур.	Max.	Units
<b>f</b> CLKOUT	Output Clock Frequency			161.1328		MHz
$\Delta f$	Frequency Stability	(Note 4)			±50	ppm
$\Phi_{NOISE}$	Phase-Noise Performance	100 Hz of Carrier		-109		dBc/Hz
	f <sub>CLKout</sub> = 161.1328 MHz (See Figure 3)	1 kHz of Carrier		-125		dBc/Hz
		10 kHz of Carrier		-132		dBc/Hz
		100 kHz of Carrier		-132		dBc/Hz
		1 MHz of Carrier		-141		dBc/Hz
		10 MHz of Carrier		-161		dBc/Hz
t <sub>jit</sub> (Φ)	RMS Phase Jitter	12 kHz to 20 MHz		0.4	0.9	ps
t <sub>jitter</sub>	Cycle to Cycle, RMS	1000 Cycles		1.5	8	ps
	Cycle to Cycle, Peak-to-Peak	1000 Cycles		15	30	ps
	Period, RMS	10,000 Cycles		1	4	ps
	Period, Peak-to-Peak	10,000 Cycles		10	20	ps
t <sub>OE/OD</sub>	Output Enable/Disable Time				200	ns
t <sub>DUTY_CYCLE</sub>	Output Clock Duty Cycle (Measured at Cross Point)		48	50	52	%
t <sub>R</sub>	Output Rise Time (20% and 80%)			250	400	ps
t <sub>F</sub>	Output Fall Time (80% and 20%)			250	400	ps
t <sub>start</sub>	Start-up Time			1	5	ms
	Aging	1 <sup>st</sup> Year			3	ppm
		Every Year After 1st			1	ppm

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

3. Measurement taken with outputs terminated with 50  $\Omega$  to V\_{DD} – 2.0 V. See Figure 4.

4. Parameter guarantee 10 years aging. Includes initial stability at 25°C, shock, vibration, and first year aging.

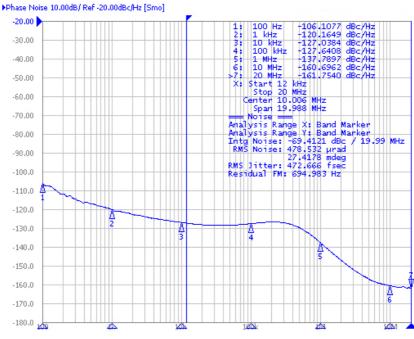


Figure 3. Typical Phase Noise Plot

#### Table 7. RELIABILITY COMPLIANCE

Parameter	Standard	Method
Shock	Mechanical	MIL-STD-833, Method 2002, Condition B
Solderability	Mechanical	MIL-STD-833, Method 2003
Vibration	Mechanical	MIL-STD-833, Method 2007, Condition A
Solvent Resistance	Mechanical	MIL-STD-202, Method 215
Thermal Shock	Environment	MIL-STD-833, Method 1011, Condition A
Moisture Level Sensitivity	Environment	MSL1 260°C per IPC/JEDEC J-STD-020D

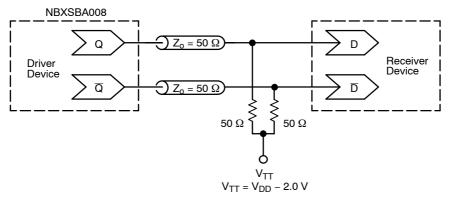


Figure 4. Typical Termination for Output Driver and Device Evaluation (See Application Note AND8020/D – Termination of ECL Logic Devices.)

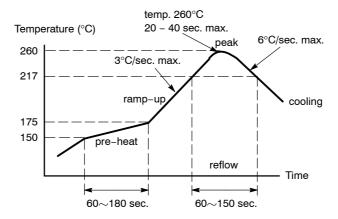
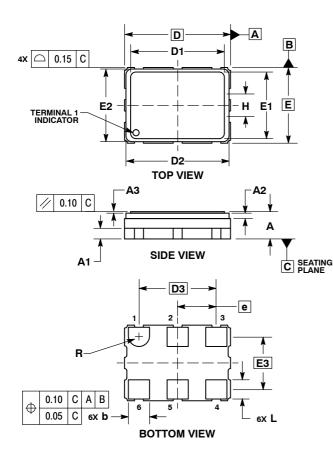


Figure 5. Recommended Reflow Soldering Profile

#### PACKAGE DIMENSIONS

6 PIN CLCC, 7x5, 2.54P CASE 848AB-01 ISSUE C

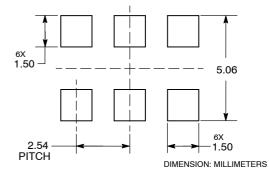


NOTES:

ASME Y14.5M, 1994. 2. CONTROLLING DIMENSION: MILLIMETERS.

	MILLIMETERS			
DIM	MIN	NOM	MAX	
Α	1.70	1.80	1.90	
A1		0.70 REF		
A2		0.36 REF		
A3	0.08	0.10	0.12	
b	1.30	1.40	1.50	
D	7.00 BSC			
D1	6.17	6.20	6.23	
D2	6.66	6.81	6.96	
D3	5.08 BSC			
E		5.00 BSC		
E1	4.37	4.40	4.43	
E2	4.65	4.80	4.95	
E3	3.49 BSC			
е	2.54 BSC			
н	1.80 REF			
L	1.17	1.27	1.37	
R	0.70 REF			

SOLDERING FOOTPRINT\*



\*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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